

Degang Chen

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/5238120/publications.pdf>

Version: 2024-02-01

182
papers

1,795
citations

567281
15
h-index

477307
29
g-index

182
all docs

182
docs citations

182
times ranked

641
citing authors

| # | ARTICLE | IF | CITATIONS |
|----|---|-----|-----------|
| 1 | All Digital Low-Overhead SAR ADC Built-In Self-Test for Fault Detection and Diagnosis. , 2022, , . | | 7 |
| 2 | Detection of Site to Site Variations from Volume Measurement Data in Multi-site Semiconductor Testing. IEEE Transactions on Instrumentation and Measurement, 2021, , 1-1. | 4.7 | 13 |
| 3 | Fast Gate Leakage Current Monitor With Large Dynamic Range. IEEE Transactions on Circuits and Systems II: Express Briefs, 2021, 68, 1690-1694. | 3.0 | 1 |
| 4 | Sub-ppm/ $^{\circ}\text{C}$ Bandgap References With Natural Basis Expansion for Curvature Cancellation. IEEE Transactions on Circuits and Systems I: Regular Papers, 2021, 68, 3551-3561. | 5.4 | 9 |
| 5 | An Ultrafast Multibit/Stage Pipelined ADC Testing and Calibration Method. IEEE Transactions on Instrumentation and Measurement, 2020, 69, 729-738. | 4.7 | 4 |
| 6 | MIRE: A Multitone Identification and Replacement Method for Multitone Spectral Test Without Requiring Coherent Sampling. IEEE Transactions on Instrumentation and Measurement, 2020, 69, 4578-4591. | 4.7 | 6 |
| 7 | A 12-Bit 125-MS/s 2.5-Bit/Cycle SAR-Based Pipeline ADC Employing a Self-Biased Gain Boosting Amplifier. IEEE Transactions on Circuits and Systems I: Regular Papers, 2020, 67, 3618-3629. | 5.4 | 5 |
| 8 | Three-Junction Bandgap Circuit with Sub 1 ppm/ $^{\circ}\text{C}$ Temperature Coefficient. , 2020, , . | | 2 |
| 9 | Least Square Based Jitter Decomposition Algorithm for a PAM4 link. , 2020, , . | | 4 |
| 10 | A Transient-Enhanced Output-Capacitorless LDO With Fast Local Loop and Overshoot Detection. IEEE Transactions on Circuits and Systems I: Regular Papers, 2020, 67, 3422-3432. | 5.4 | 43 |
| 11 | An 8-bit Low-Cost String DAC With Gradient Errors Suppression to Achieve 16-bit Linearity. IEEE Transactions on Circuits and Systems I: Regular Papers, 2020, 67, 2157-2168. | 5.4 | 8 |
| 12 | An Integrated Circuit Solution to Johnson Noise Thermometry Using Low-Cost and Fast CMOS Technology. IEEE Sensors Journal, 2019, 19, 3240-3251. | 4.7 | 3 |
| 13 | Bandgap Voltage V_{GO} Extraction with Two-Temperature Trimming for Designing Sub-ppm/ $^{\circ}\text{C}$ Voltage References. , 2019, , . | | 5 |
| 14 | Built-in self-test and self-calibration for analog and mixed signal circuits. , 2019, , . | | 0 |
| 15 | Low-Cost, High-Precision DAC Design Based on Ordered Element Matching. IEEE Transactions on Circuits and Systems I: Regular Papers, 2019, 66, 502-512. | 5.4 | 7 |
| 16 | Fast and Accurate Decomposition of Deterministic Jitter Components in High-Speed Links. IEEE Transactions on Electromagnetic Compatibility, 2019, 61, 217-225. | 2.2 | 9 |
| 17 | High-Purity Sine Wave Generation Using Nonlinear DAC With Predistortion Based on Low-Cost Accurate DAC-ADC Co-Testing. IEEE Transactions on Instrumentation and Measurement, 2018, 67, 279-287. | 4.7 | 15 |
| 18 | Improving Time-Efficiency of Fault-Coverage Simulation for MOS Analog Circuit. IEEE Transactions on Circuits and Systems I: Regular Papers, 2018, 65, 1664-1674. | 5.4 | 12 |

| # | ARTICLE | IF | CITATIONS |
|----|---|-----|-----------|
| 19 | A Transient-Enhanced Fully-Integrated LDO Regulator for SoC Application. , 2018, , . | | 11 |
| 20 | USER-SMILE: Ultrafast Stimulus Error Removal and Segmented Model Identification of Linearity Errors for ADC Built-in Self-Test. IEEE Transactions on Circuits and Systems I: Regular Papers, 2018, 65, 2059-2069. | 5.4 | 22 |
| 21 | A low-cost jitter separation and ADC spectral testing method without requiring coherent sampling. , 2018, , . | | 0 |
| 22 | Cost-Effective High Purity Signal Generator Using Pre-distortion. , 2018, , . | | 2 |
| 23 | Accurate Spectral Testing with Impure Test Stimulus for Multi-tone Test. , 2018, , . | | 5 |
| 24 | Transparent side channel trigger mechanism on analog circuits with PAAST hardware Trojans. , 2018, , . | | 8 |
| 25 | Low-cost and accurate DAC linearity test with ultrafast segmented model identification of linearity errors and removal of measurement errors (uSMILE-ROME). , 2018, , . | | 4 |
| 26 | Cost-effective accurate DAC-ADC co-testing and DAC linearization. , 2018, , . | | 4 |
| 27 | A High Constancy Rail-to-rail Level Shift Generator for SEIR-based BIST circuit for ADCs. , 2018, , . | | 4 |
| 28 | Concurrent Sampling with Local Digitization “An Alternative to Analog Test Bus. , 2018, , . | | 4 |
| 29 | Accurate jitter decomposition in high-speed links. , 2017, , . | | 4 |
| 30 | A low-cost method for separation and accurate estimation of ADC noise, aperture jitter, and clock jitter. , 2017, , . | | 7 |
| 31 | Efficient Verification Against Undesired Operating Points for MOS Analog Circuits. IEEE Transactions on Circuits and Systems I: Regular Papers, 2017, 64, 2134-2145. | 5.4 | 3 |
| 32 | Algorithms for Accurate Spectral Analysis in the Presence of Arbitrary Noncoherency and Large Distortion. IEEE Transactions on Instrumentation and Measurement, 2017, 66, 2556-2565. | 4.7 | 10 |
| 33 | ADC Spectral Testing with Signal Amplitude Drift and Simultaneous Non-coherent Sampling. Journal of Electronic Testing: Theory and Applications (JETTA), 2017, 33, 305-313. | 1.2 | 2 |
| 34 | Accurate Spectral Testing With Arbitrary Noncoherency in Sampling and Simultaneous Drifts in Amplitude and Frequency. IEEE Transactions on Instrumentation and Measurement, 2017, 66, 1002-1012. | 4.7 | 5 |
| 35 | A digital clock-less pulse stretcher with application in deep sub-nanosecond pulse detection. , 2017, , . | | 1 |
| 36 | An on-chip ADC BIST solution and the BIST enabled calibration scheme. , 2017, , . | | 8 |

| # | ARTICLE | IF | CITATIONS |
|----|--|-----|-----------|
| 37 | Systematic and random mismatch characterization in device arrays. , 2017, , . | | 0 |
| 38 | Practical linear and quadratic gradient errors suppression techniques in string DACs. , 2017, , . | | 2 |
| 39 | Accurate and robust spectral testing with relaxed instrumentation requirements. , 2017, , . | | 1 |
| 40 | Accurate Spectral Testing With Non-Coherent Sampling for Multi-Tone Test. IEEE Transactions on Circuits and Systems II: Express Briefs, 2017, 64, 1357-1361. | 3.0 | 6 |
| 41 | Accurate spectral testing of the signals with amplitude drift. , 2017, , . | | 0 |
| 42 | Technique for generating timing skew resistant time-interleaved signals. , 2017, , . | | 0 |
| 43 | A voltage reference generator targeted at extracting the silicon bandgap V_{go} from V_{be} . , 2017, , . | | 4 |
| 44 | Toward complete analog fault coverage with minimal observation points using a fault propagation graph. , 2016, , . | | 1 |
| 45 | New strategies in removing non-coherency from signals with large distortion to noise ratios. , 2016, , . | | 7 |
| 46 | Low cost ultra-pure sine wave generation with self calibration. , 2016, , . | | 7 |
| 47 | Accurate Spectral Testing With Impure Source and Noncoherent Sampling. IEEE Transactions on Instrumentation and Measurement, 2016, 65, 2454-2463. | 4.7 | 10 |
| 48 | New Strategies in Removing Noncoherency From Signals With Large Distortion-to-Noise Ratios. IEEE Transactions on Circuits and Systems II: Express Briefs, 2016, 63, 1136-1140. | 3.0 | 6 |
| 49 | Low-cost dithering generator for accurate ADC linearity test. , 2016, , . | | 9 |
| 50 | Accurate linearity testing with impure sinusoidal stimulus robust against flicker noise. , 2016, , . | | 4 |
| 51 | Accurate spectral testing with non-coherent sampling for large distortion to noise ratios. , 2016, , . | | 12 |
| 52 | Hardware Trojans embedded in the dynamic operation of analog and mixed-signal circuits. , 2015, , . | | 16 |
| 53 | Extracting random jitter and sinusoidal jitter in ADC output with a single frequency test. IEICE Electronics Express, 2015, 12, 20150742-20150742. | 0.8 | 1 |
| 54 | Cascode and transconductance with capacitances feedback compensation for multistage amplifiers driving no load and 1nF capacitive load. , 2015, , . | | 2 |

| # | ARTICLE | IF | CITATIONS |
|----|--|-----|-----------|
| 55 | A Comparative Study of State-of-the-Art High-Performance Spectral Test Methods. IEEE Design and Test, 2015, 32, 26-35. | 1.2 | 8 |
| 56 | A low cost jitter separation and characterization method. , 2015, , . | | 7 |
| 57 | Ultrafast stimulus error removal algorithm for ADC linearity test. , 2015, , . | | 17 |
| 58 | Switched-compensation technique in switched-capacitor circuit for achieving fast settling performance. , 2015, , . | | 0 |
| 59 | Accurate spectral testing of analog-to-digital converters with frequency drift using phase correction and averaging. , 2015, , . | | 2 |
| 60 | A slew-rate enhancement technique for fully differential amplifier without inducing Trojan state. , 2015, , . | | 3 |
| 61 | Effect of flicker noise on SEIR for accurate ADC linearity testing. , 2015, , . | | 4 |
| 62 | Performance enhancement induced Trojan states in op-amps, their detection and removal. , 2015, , . | | 11 |
| 63 | A simple ramp generator with level spreading for SEIR based ADC BIST circuit. , 2015, , . | | 1 |
| 64 | High-constancy offset generator robust to CDAC nonlinearity for SEIR-based ADC BIST. , 2015, , . | | 3 |
| 65 | A novel 20-bit R-2R DAC structure based on ordered element matching. , 2015, , . | | 7 |
| 66 | An integrated circuit solution of thermal noise thermometer with cascaded pre-amplifier and 6-bit resolution analog-to-digital converter. , 2015, , . | | 2 |
| 67 | A calibration technique for SAR analog-to-digital converter based on INL testing with quantization bits and redundant bit. , 2015, , . | | 5 |
| 68 | A low cost jitter estimation and ADC spectral testing method. , 2015, , . | | 6 |
| 69 | Auto-identification of positive feedback loops in multi-state vulnerable circuits. , 2014, , . | | 8 |
| 70 | A high gain operational amplifier via an efficient conductance cancellation technique. , 2014, , . | | 2 |
| 71 | A graphical method for identifying positive feedback loops automatically in self-biasing circuit for determining the uniqueness of operating points. , 2014, , . | | 1 |
| 72 | Efficient Spectral Testing With Clipped and Noncoherently Sampled Data. IEEE Transactions on Instrumentation and Measurement, 2014, 63, 1451-1460. | 4.7 | 5 |

| # | ARTICLE | IF | CITATIONS |
|----|--|-----|-----------|
| 73 | A CMOS supply-insensitive with 13ppm/ $^{\circ}\text{C}$ temperature coefficient current reference. , 2014, , . | | 8 |
| 74 | A simple slew rate enhancement technique with improved linearity and preserved small signal performance. , 2014, , . | | 12 |
| 75 | Hardware trojan state detection for analog circuits and systems. , 2014, , . | | 9 |
| 76 | Identification and break of positive feedback loops in Trojan States Vulnerable Circuits. , 2014, , . | | 15 |
| 77 | Efficient analog verification against Trojan states using divide and contraction method. , 2014, , . | | 8 |
| 78 | Accurate and efficient method of jitter and noise separation and its application to ADC testing. , 2014, , . | | 8 |
| 79 | A high resolution and high accuracy R-2R DAC based on ordered element matching. , 2013, , . | | 11 |
| 80 | A CMOS on-chip temperature sensor with $\pm 0.21^{\circ}\text{C}$ 0.17°C inaccuracy from $\pm 20^{\circ}\text{C}$ to 100°C . , 2013, , . | | 11 |
| 81 | Soft Elastomeric Capacitor Network for Strain Sensing Over Large Surfaces. IEEE/ASME Transactions on Mechatronics, 2013, 18, 1647-1654. | 5.8 | 81 |
| 82 | FIRE: A Fundamental Identification and Replacement Method for Accurate Spectral Test Without Requiring Coherency. IEEE Transactions on Instrumentation and Measurement, 2013, 62, 3015-3025. | 4.7 | 33 |
| 83 | Reliability degradation with electrical, thermal and thermal gradient stress in interconnects. , 2013, , . | | 3 |
| 84 | Accurate full spectrum test robust to simultaneous non-coherent sampling and amplitude clipping. , 2013, , . | | 6 |
| 85 | A 15-bit binary-weighted current-steering DAC with ordered element matching. , 2013, , . | | 11 |
| 86 | An Order-Statistics Based Matching Strategy for Circuit Components in Data Converters. IEEE Transactions on Circuits and Systems I: Regular Papers, 2013, 60, 11-24. | 5.4 | 19 |
| 87 | High resolution ADC spectral test with known impure source and non-coherent sampling. , 2013, , . | | 5 |
| 88 | ADC spectral testing allowing amplitude clipping. , 2013, , . | | 7 |
| 89 | Practical methods for verifying removal of Trojan stable operating points. , 2013, , . | | 16 |
| 90 | A low cost method for testing offset and gain error for ADC BIST. , 2012, , . | | 3 |

| # | ARTICLE | IF | CITATIONS |
|-----|---|-----|-----------|
| 91 | An on-chip inductive impedance measurement method with adaptive measurement range control for MWM-array based NDE applications. , 2012, , . | | 1 |
| 92 | ADC jitter estimation using a single frequency test without requiring coherent sampling. IEICE Electronics Express, 2012, 9, 1485-1491. | 0.8 | 3 |
| 93 | An Accurate and Cost-Effective Jitter Measurement Technique Using a Single Test Frequency. Journal of Electronic Testing: Theory and Applications (JETTA), 2012, 28, 733-743. | 1.2 | 2 |
| 94 | On Chip Signal Generators for Low Overhead ADC BIST. Journal of Electronic Testing: Theory and Applications (JETTA), 2012, 28, 615-623. | 1.2 | 4 |
| 95 | Reliability modeling of metal interconnects with time-dependent electrical and thermal stress. , 2012, , . | | 2 |
| 96 | A method for accurate full spectrum testing without requiring coherency. , 2012, , . | | 1 |
| 97 | Performance verification of start-up circuits in reference generators. , 2012, , . | | 6 |
| 98 | Algorithm for dramatically improved efficiency in ADC linearity test. , 2012, , . | | 31 |
| 99 | A compact low-power supply-insensitive CMOS current reference. , 2012, , . | | 10 |
| 100 | New Spectral Leakage-Removing Method for Spectral Testing of Approximate Sinusoidal Signals. IEEE Transactions on Instrumentation and Measurement, 2012, 61, 1296-1306. | 4.7 | 26 |
| 101 | A 2-FFT method for on-chip spectral testing without requiring coherency. , 2011, , . | | 8 |
| 102 | SNR measurement based on linearity test for ADC BIST. , 2011, , . | | 5 |
| 103 | A novel robust and accurate spectral testing method for non-coherent sampling. , 2011, , . | | 20 |
| 104 | A faster method for accurate spectral testing without requiring coherent sampling. , 2011, , . | | 7 |
| 105 | Linear vt-based temperature sensors with low process sensitivity and improved power supply headroom. , 2011, , . | | 13 |
| 106 | ADC spectral performance measurement uncertainty in DFT method. , 2011, , . | | 1 |
| 107 | Multi-site on-chip current sensor for electromigration monitoring. , 2011, , . | | 3 |
| 108 | Multi-threshold transistors cell for Low Voltage temperature sensing applications. , 2011, , . | | 12 |

| # | ARTICLE | IF | CITATIONS |
|-----|--|-----|-----------|
| 109 | INL based dynamic performance estimation for ADC BIST. , 2010, , . | | 12 |
| 110 | Detailed analyses in prediction of capacitive-mismatch-induced offset in dynamic comparators. , 2010, , . | | 0 |
| 111 | Phase control of triangular stimulus generator for ADC BIST. , 2010, , . | | 5 |
| 112 | A new method for estimating spectral performance of ADC from INL. , 2010, , . | | 4 |
| 113 | A faster and accurate method for spectral testing applicable to noncoherent data. , 2010, , . | | 5 |
| 114 | Highly linear very compact untrimmed on-chip temperature sensor with second and third order temperature compensation. , 2010, , . | | 14 |
| 115 | New calibration technique for current-steering DACs. , 2010, , . | | 23 |
| 116 | A linear differential output of threshold-based CMOS temperature sensor with enhanced signal range. , 2010, , . | | 1 |
| 117 | Systematic characterization of subthreshold- mosfets-based voltage references for ultra low power low voltage applications. , 2010, , . | | 5 |
| 118 | Sensorless temperature measurement based on ADC Input noise measurement. , 2010, , . | | 4 |
| 119 | Optimal area and impedance allocation for dual - string DACs. , 2009, , . | | 0 |
| 120 | Code-Density Test of Analog-to-Digital Converters Using Single Low-Linearity Stimulus Signal. IEEE Transactions on Instrumentation and Measurement, 2009, 58, 2679-2685. | 4.7 | 17 |
| 121 | High-Resolution ADC Linearity Testing Using a Fully Digital-Compatible BIST Strategy. IEEE Transactions on Instrumentation and Measurement, 2009, 58, 2697-2705. | 4.7 | 18 |
| 122 | Stimulus generator for SEIR method based ADC BIST. , 2009, , . | | 11 |
| 123 | New sequence switching and layout technique for high-speed high-accuracy current-steering DACs. , 2009, , . | | 8 |
| 124 | Analyses of Static and Dynamic Random Offset Voltages in Dynamic Comparators. IEEE Transactions on Circuits and Systems I: Regular Papers, 2009, 56, 911-919. | 5.4 | 137 |
| 125 | Cost effective signal generators for ADC BIST. , 2009, , . | | 16 |
| 126 | Testing of Precision DAC Using Low-Resolution ADC With Wobbling. IEEE Transactions on Instrumentation and Measurement, 2008, 57, 940-946. | 4.7 | 17 |

| # | ARTICLE | IF | CITATIONS |
|-----|---|-----|-----------|
| 127 | A simple and accurate method to predict offset voltage in dynamic comparators. , 2008, , . | | 4 |
| 128 | A detailed analysis of nonideal effects on high precision bandgap voltage references. , 2008, , . | | 2 |
| 129 | An overview and behavioral modeling of higher order multi-bit ΣΔ A/D converters. , 2008, , . | | 3 |
| 130 | On-chip at-speed linearity testing of high-resolution high-speed DACs using DDEM ADCs with dithering. , 2008, , . | | 5 |
| 131 | System identification -based reduced-code testing for pipeline ADCsâ€™ linearity test. , 2008, , . | | 2 |
| 132 | Deterministic DEM DAC Performance Analysis. , 2007, , . | | 0 |
| 133 | Robust High-Gain Amplifier Design Using Dynamical Systems and Bifurcation Theory With Digital Postprocessing Techniques. IEEE Transactions on Circuits and Systems Part 1: Regular Papers, 2007, 54, 964-973. | 0.1 | 7 |
| 134 | Code-Density Test of Analog-to-Digital Converters Using Single Low-Linearity Stimulus Signal. , 2007, , . | | 7 |
| 135 | A fully digital-compatible BIST strategy for ADC linearity testing. , 2007, , . | | 17 |
| 136 | Testing High-Resolution ADCs With Low-Resolution/Accuracy Deterministic Dynamic Element Matched DACs. IEEE Transactions on Instrumentation and Measurement, 2007, 56, 1753-1762. | 4.7 | 23 |
| 137 | SEIR Linearity Testing of Precision A/D Converters in Nonstationary Environments With Center-Symmetric Interleaving. IEEE Transactions on Instrumentation and Measurement, 2007, 56, 1776-1785. | 4.7 | 28 |
| 138 | Output tracking control of a one-link flexible manipulator via causal inversion. IEEE Transactions on Control Systems Technology, 2006, 14, 141-148. | 5.2 | 25 |
| 139 | Yield enhancement with optimal area allocation for ratio-critical analog circuits. IEEE Transactions on Circuits and Systems Part 1: Regular Papers, 2006, 53, 534-553. | 0.1 | 17 |
| 140 | Linearity Test of Analog-to-Digital Converters Using Kalman Filtering. IEEE International Test Conference (TC), 2006, , . | 0.0 | 10 |
| 141 | A Deterministic Dynamic Element Matching Approach for Testing High-Resolution ADCs With Low-Accuracy Excitations. IEEE Transactions on Instrumentation and Measurement, 2006, 55, 902-915. | 4.7 | 13 |
| 142 | Accurate Testing of Analog-to-Digital Converters Using Low Linearity Signals With Stimulus Error Identification and Removal. IEEE Transactions on Instrumentation and Measurement, 2005, 54, 1188-1199. | 4.7 | 110 |
| 143 | Feedback control strategies for a nonholonomic mobile robot using a nonlinear oscillator. Journal of Field Robotics, 1999, 16, 237-248. | 0.7 | 6 |
| 144 | A finite energy property of stable inversion to nonminimum phase nonlinear systems. IEEE Transactions on Automatic Control, 1998, 43, 1170-1174. | 5.7 | 12 |

| # | ARTICLE | IF | CITATIONS |
|-----|---|-----|-----------|
| 145 | Tip trajectory tracking of a flexible-joint robot using stable inversion. , 1997, , . | | 1 |
| 146 | Stable inversion of nonlinear non-minimum phase systems. International Journal of Control, 1996, 64, 81-97. | 1.9 | 122 |
| 147 | Asymptotic feedback stabilization of a nonholonomic mobile robot using a nonlinear oscillator. , 0, , . | | 4 |
| 148 | Automatic landing control using H_∞ control and stable inversion. , 0, , . | | 7 |
| 149 | Robust inversion-based learning control for nonminimum phase systems. , 0, , . | | 1 |
| 150 | A dynamic element matching approach to ADC testing. , 0, , . | | 9 |
| 151 | A blind identification algorithm for digital calibration of pipelined ADC. , 0, , . | | 0 |
| 152 | Inversion-based adaptive learning control for a one-link flexible manipulator. , 0, , . | | 0 |
| 153 | A modified histogram approach for accurate self-characterization of analog-to-digital converters. , 0, , . | | 15 |
| 154 | Optimal loop parameter design of charge pump PLLs for jitter transfer characteristic optimization. , 0, , . | | 4 |
| 155 | Equivalent gain analysis for nonlinear operational amplifiers. , 0, , . | | 2 |
| 156 | Tip trajectory tracking for a one-link flexible manipulator using causal inversion. , 0, , . | | 1 |
| 157 | A blind identification approach to digital calibration of analog-to-digital converters for built-in-self-test. , 0, , . | | 11 |
| 158 | Output tracking control of nonminimum phase systems via causal inversion. , 0, , . | | 1 |
| 159 | A deterministic dynamic element matching approach to ADC testing. , 0, , . | | 11 |
| 160 | Experimental evaluation and validation of a BIST algorithm for characterization of A/D converter performance. , 0, , . | | 4 |
| 161 | Linearity testing of precision analog-to-digital converters using stationary nonlinear inputs. , 0, , . | | 28 |
| 162 | Optimum area allocation for resistors and capacitors in continuous-time monolithic filters. , 0, , . | | 2 |

| # | ARTICLE | IF | CITATIONS |
|-----|---|----|-----------|
| 163 | Testing high resolution ADCs using deterministic dynamic element matching. , 0, , . | | 8 |
| 164 | Parameter optimization of deterministic dynamic element matching DACs for accurate and cost-effective ADC testing. , 0, , . | | 8 |
| 165 | A background digital self-calibration scheme for pipelined ADCs based on transfer curve estimation. , 0, , . | | 1 |
| 166 | Testing high resolution ADCs with low resolution/accuracy deterministic dynamic element matched DACs. , 0, , . | | 4 |
| 167 | A novel 1.5 V CMFB CMOS down-conversion mixer design for IEEE 802.11 A WLAN systems. , 0, , . | | 7 |
| 168 | An SoC compatible linearity test approach for precision ADCs using easy-to-generate sinusoidal stimuli. , 0, , . | | 9 |
| 169 | Fast implementation of a linearity test approach for high-resolution ADCs using non-linear ramp signals. , 0, , . | | 6 |
| 170 | A Two-Step DDEM ADC for Accurate and Cost-Effective DAC Testing. , 0, , . | | 5 |
| 171 | A Segmented Thermometer Coded DAC with Deterministic Dynamic Element Matching for High Resolution ADC Test. , 0, , . | | 2 |
| 172 | An N th /sup<Order Central Symmetrical Layout Pattern for Nonlinear Gradients Cancellation. , 0, , . | | 8 |
| 173 | A Test Strategy for Time-to-Digital Converters Using Dynamic Element Matching and Dithering. , 0, , . | | 1 |
| 174 | High-performance adc linearity test using low-precision signals in non-stationary environments. , 0, , . | | 15 |
| 175 | A Cost-Effective Histogram Test-Based Algorithm for Digital Calibration of High-Precision Pipelined ADCs. , 0, , . | | 12 |
| 176 | Dither Incorporated Deterministic Dynamic Element Matching for High Resolution ADC Test Using Extremely Low Resolution DACs. , 0, , . | | 5 |
| 177 | A Digital Self-Calibration Algorithm for ADCs Based on Histogram Test Using Low-Linearity Input Signals. , 0, , . | | 13 |
| 178 | Characterization of a current-mode bandgap circuit structure for high-precision reference applications. , 0, , . | | 3 |
| 179 | Explicit Characterization of Bandgap References. , 0, , . | | 4 |
| 180 | Linearity Test for High Resolution DACs Using Low-Accuracy DDEM Flash ADCs. , 0, , . | | 2 |

| # | ARTICLE | IF | CITATIONS |
|-----|---|----|-----------|
| 181 | A Self-Calibrated Bandgap Voltage Reference with 0.5 ppm/°C Temperature Coefficient. , 0, , . | | 3 |
| 182 | Causal inversion of nonminimum phase systems. , 0, , . | | 10 |